



# **IEEE802.3 4P Task Force Channel Pair To Pair Resistance Imbalance**

**Investigation of a low resistance  
connector**

# IEC 60603-7 - Summary of specifications

- › **Input to output d.c. resistance:**  
*200m $\Omega$  maximum*
- › **Initial contact resistance:**  
*20m $\Omega$  maximum*
- › **Input to output d.c.  
resistance unbalance:**  
*50m $\Omega$  maximum*
- › **Environmental or mechanical “aging”:**  
*Contact resistance 20m $\Omega$  maximum  
change from initial*

# IEC 60603-7

- For the worst case model of the Ad-hoc, (minimum resistance, maximum unbalance) the maximum values according 60603-7 ( $200m\Omega$  /  $50m\Omega$ ) *are probably too high/not relevant.*

*But also a low resistance connector is affected by aging (environmental stress, mechanical operation,..) which would increase the initial resistance unbalance over lifetime.*

- To increase the database for the Ad-hoc model, this document lists the resistance test data of a specific low resistance connector.

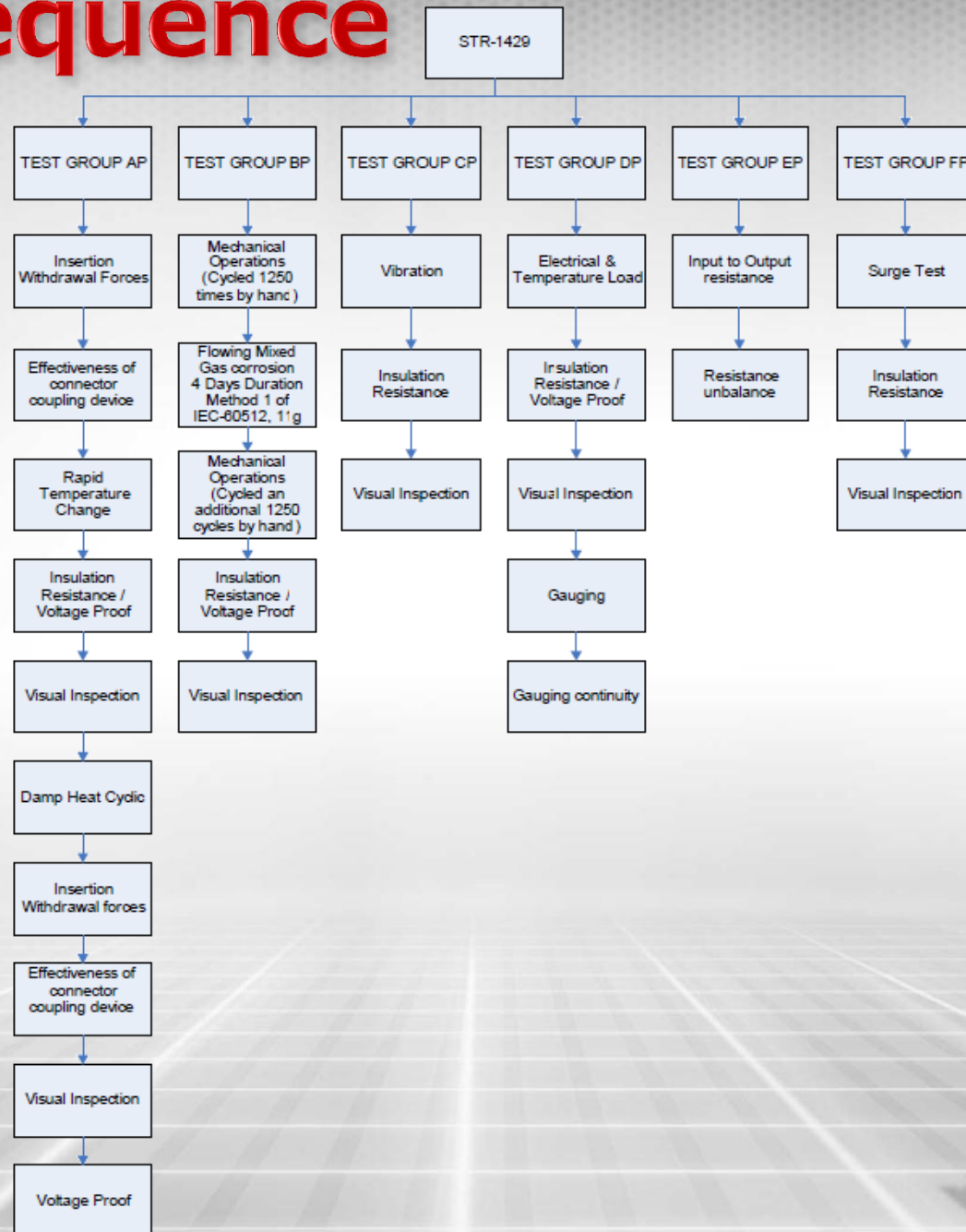


# Connector

- › **Product:**  
**Short Top Entry**  
**RJ-45 connector with low**  
**input to output resistance.**
- › **Testing and test references**  
**according IEC 60603-7**
- › **Total quantity: 52 Samples:**



# Test Sequence



# Results:

- **EP7 Input to output resistance:**  
**23.34/20.19/19.14** (mΩ Max/Mean/Min)
- **EP8 Resistance unbalance (initial):**  
**4.2 mΩ maximum**
- **P3 Initial Contact Resistance:**  
**11.1 / 7.9 / 6.9** (mΩ Max/Mean/Min)
- **AP9 Thermal Stress / Damp heat**  
**Resistance change from initial:**  
**3.1 / 1.3 / -0.9** (mΩ Max/Mean/Min)

# Results:

- **BP6** (FMG/Corrosion, mechanical operation)  
Resistance change from initial:  
**3.1 / 1.3 / -0.9** (mΩ Max/Mean/Min)
- **CP2** (Vibration)  
Resistance change from initial:  
**0.3 / -0.4 / -1.3** (mΩ Max/Mean/Min)
- **DP5** (Electrical load and temperature)  
Resistance change from initial:  
**3.1 / 0.0 / -3.4** (mΩ Max/Mean/Min)

# Summary

## ➤ Based on these test results the worst case would be:

- Minimum initial resistance:  
**19.14 mΩ**
- Maximum initial resistance (23.34 mΩ )  
+ maximum change after aging (3.1 mΩ\*)  
**= 26.44 mΩ**  
(7.3mΩ worst case resistance difference)

(\*) It has to be considered that the investigated jack has NiPd plating which offers a high contact reliability.  
A similar jack with a low quality plating could show a higher change of the contact resistance after aging.